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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	42960
Number of Logic Elements/Cells	549888
Total RAM Bits	23298048
Number of I/O	1200
Number of Gates	-
Voltage - Supply	0.95V ~ 1.05V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	1760-BBGA, FCBGA
Supplier Device Package	1760-FCBGA (42.5x42.5)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xc6vlx550t-1ffg1760i

Table 3: DC Characteristics Over Recommended Operating Conditions (1)(2)

Symbol	Description	Min	Typ	Max	Units
V_{DRINT}	Data retention V_{CCINT} voltage (below which configuration data might be lost)	0.75	—	—	V
V_{DRI}	Data retention V_{CCAUX} voltage (below which configuration data might be lost)	2.0	—	—	V
I_{REF}	V_{REF} leakage current per pin	—	—	10	μA
I_L	Input or output leakage current per pin (sample-tested)	—	—	10	μA
$C_{IN}^{(3)}$	Die input capacitance at the pad	—	—	8	pF
I_{RPU}	Pad pull-up (when selected) @ $V_{IN} = 0V$, $V_{CCO} = 2.5V$	20	—	80	μA
	Pad pull-up (when selected) @ $V_{IN} = 0V$, $V_{CCO} = 1.8V$	8	—	40	μA
	Pad pull-up (when selected) @ $V_{IN} = 0V$, $V_{CCO} = 1.5V$	5	—	30	μA
	Pad pull-up (when selected) @ $V_{IN} = 0V$, $V_{CCO} = 1.2V$	1	—	20	μA
I_{RPD}	Pad pull-down (when selected) @ $V_{IN} = 2.5V$	3	—	80	μA
I_{BATT}	Battery supply current	—	—	150	nA
n	Temperature diode ideality factor	—	1.0002	—	n
r	Series resistance	—	5	—	Ω

Notes:

1. Typical values are specified at nominal voltage, 25°C.
2. Maximum value specified for worst case process at 25°C.
3. This measurement represents the die capacitance at the pad, not including the package.

Table 16: GTX Transceiver Quiescent Supply Current (per Lane) ⁽¹⁾⁽²⁾⁽³⁾

Symbol	Description	Typ ⁽⁴⁾	Max	Units
IMGTAVTTQ	Quiescent MGTAVTT supply current for one GTX transceiver	0.9	Note 2	mA
IMGTAVCCQ	Quiescent MGTAVCC supply current for one GTX transceiver	3.5		mA

Notes:

1. Device powered and unconfigured.
2. Currents for conditions other than values specified in this table can be obtained by using the XPE or XPA tools.
3. GTX transceiver quiescent supply current for an entire device can be calculated by multiplying the values in this table by the number of available GTX transceivers.
4. Typical values are specified at nominal voltage, 25°C.

GTX Transceiver DC Input and Output Levels

Table 17 summarizes the DC output specifications of the GTX transceivers in Virtex-6 FPGAs. Consult [UG366: Virtex-6 FPGA GTX Transceivers User Guide](#) for further details.

Table 17: GTX Transceiver DC Specifications

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
DV _{PPIN}	Differential peak-to-peak input voltage	External AC coupled ≤ 4.25 Gb/s	125	–	2000	mV
		External AC coupled > 4.25 Gb/s	175	–	2000	mV
V _{IN}	Absolute input voltage	DC coupled MGTAVTT = 1.2V	–400	–	MGTAVTT	mV
V _{CMIN}	Common mode input voltage	DC coupled MGTAVTT = 1.2V	–	2/3 MGTAVTT	–	mV
DV _{PPOUT}	Differential peak-to-peak output voltage ⁽¹⁾	Transmitter output swing is set to maximum setting	–	–	1000	mV
V _{CMOUTDC}	DC common mode output voltage.	Equation based	MGTAVTT – DV _{PPOUT} /4			mV
R _{IN}	Differential input resistance		80	100	130	Ω
R _{OUT}	Differential output resistance		80	100	120	Ω
T _{OSKEW}	Transmitter output pair (TXP and TXN) intra-pair skew		–	2	8	ps
C _{EXT}	Recommended external AC coupling capacitor ⁽²⁾		–	100	–	nF

Notes:

1. The output swing and preemphasis levels are programmable using the attributes discussed in [UG366: Virtex-6 FPGA GTX Transceivers User Guide](#) and can result in values lower than reported in this table.
2. Other values can be used as appropriate to conform to specific protocols and standards.

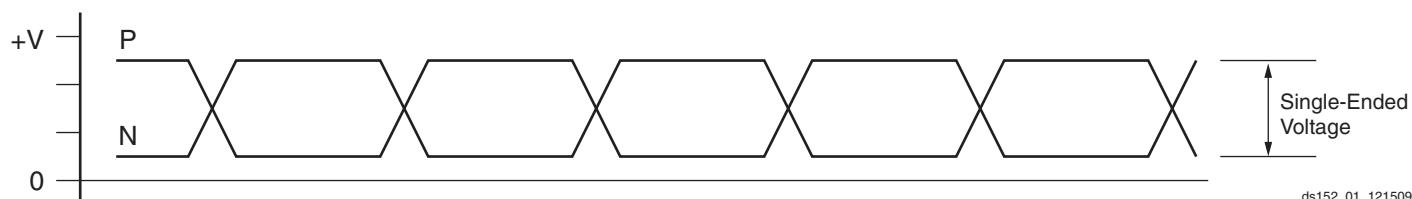


Figure 1: Single-Ended Peak-to-Peak Voltage

Table 23: GTX Transceiver Transmitter Switching Characteristics

Symbol	Description	Condition	Min	Typ	Max	Units
F_{GTXTX}	Serial data rate range		0.480	—	F_{GTXMAX}	Gb/s
T_{RTX}	TX Rise time	20%–80%	—	120	—	ps
T_{FTX}	TX Fall time	80%–20%	—	120	—	ps
T_{LLSKEW}	TX lane-to-lane skew ⁽¹⁾		—	—	350	ps
$V_{TXOOBVDPDPP}$	Electrical idle amplitude		—	—	15	mV
$T_{TXOOBTTRANSITION}$	Electrical idle transition time		—	—	75	ns
$TJ_{6.5}$	Total Jitter ⁽²⁾⁽³⁾	6.5 Gb/s	—	—	0.33	UI
$DJ_{6.5}$	Deterministic Jitter ⁽²⁾⁽³⁾		—	—	0.17	UI
$TJ_{5.0}$	Total Jitter ⁽²⁾⁽³⁾	5.0 Gb/s	—	—	0.33	UI
$DJ_{5.0}$	Deterministic Jitter ⁽²⁾⁽³⁾		—	—	0.15	UI
$TJ_{4.25}$	Total Jitter ⁽²⁾⁽³⁾	4.25 Gb/s	—	—	0.33	UI
$DJ_{4.25}$	Deterministic Jitter ⁽²⁾⁽³⁾		—	—	0.14	UI
$TJ_{3.75}$	Total Jitter ⁽²⁾⁽³⁾	3.75 Gb/s	—	—	0.34	UI
$DJ_{3.75}$	Deterministic Jitter ⁽²⁾⁽³⁾		—	—	0.16	UI
$TJ_{3.125}$	Total Jitter ⁽²⁾⁽³⁾	3.125 Gb/s	—	—	0.2	UI
$DJ_{3.125}$	Deterministic Jitter ⁽²⁾⁽³⁾		—	—	0.1	UI
$TJ_{3.125L}$	Total Jitter ⁽²⁾⁽³⁾	3.125 Gb/s ⁽⁴⁾	—	—	0.35	UI
$DJ_{3.125L}$	Deterministic Jitter ⁽²⁾⁽³⁾		—	—	0.16	UI
$TJ_{2.5}$	Total Jitter ⁽²⁾⁽³⁾	2.5 Gb/s ⁽⁵⁾	—	—	0.20	UI
$DJ_{2.5}$	Deterministic Jitter ⁽²⁾⁽³⁾		—	—	0.08	UI
$TJ_{1.25}$	Total Jitter ⁽²⁾⁽³⁾	1.25 Gb/s ⁽⁶⁾	—	—	0.15	UI
$DJ_{1.25}$	Deterministic Jitter ⁽²⁾⁽³⁾		—	—	0.06	UI
TJ_{600}	Total Jitter ⁽²⁾⁽³⁾	600 Mb/s	—	—	0.1	UI
DJ_{600}	Deterministic Jitter ⁽²⁾⁽³⁾		—	—	0.03	UI
TJ_{480}	Total Jitter ⁽²⁾⁽³⁾	480 Mb/s	—	—	0.1	UI
DJ_{480}	Deterministic Jitter ⁽²⁾⁽³⁾		—	—	0.03	UI

Notes:

1. Using same REFCLK input with TXENPMAPHASEALIGN enabled for up to 12 consecutive transmitters (three fully populated GTX Quads).
2. Using PLL_DIVSEL_FB = 2, 20-bit internal data width. These values are NOT intended for protocol specific compliance determinations.
3. All jitter values are based on a bit-error ratio of 10^{-12} .
4. PLL frequency at 1.5625 GHz and OUTDIV = 1.
5. PLL frequency at 2.5 GHz and OUTDIV = 2.
6. PLL frequency at 2.5 GHz and OUTDIV = 4.

Figure 4 shows the timing parameters in Table 27.

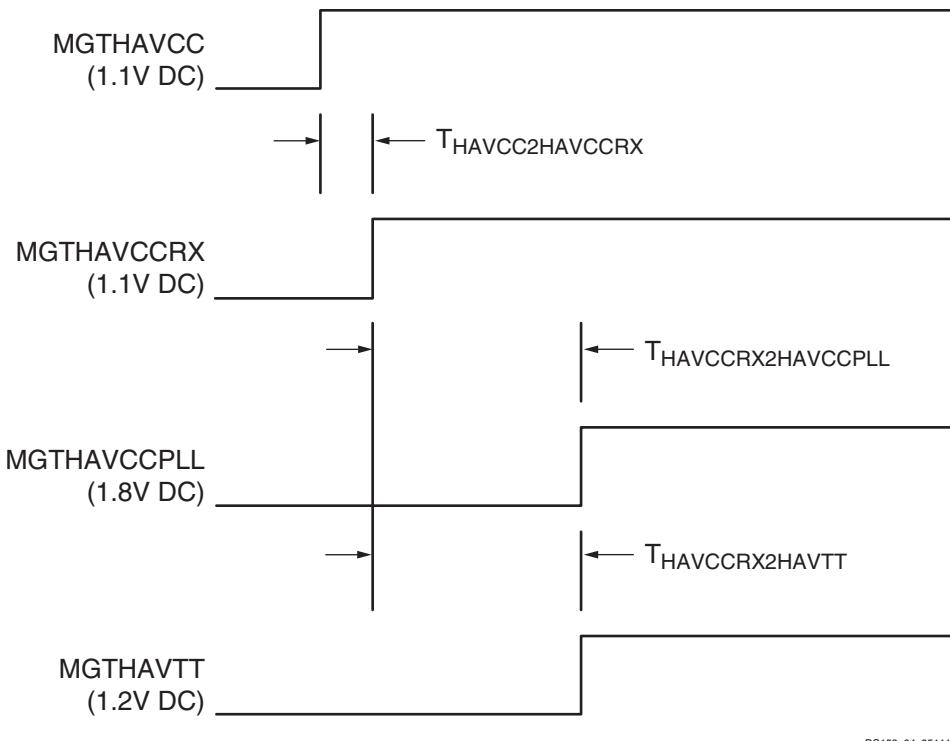


Figure 4: GTH Transceiver Power Supply Power-On Sequencing

Table 28: GTH Transceiver Supply Current

Symbol	Description	Typ ⁽¹⁾	Max	Units
IMGTHAVCC	MGTHAVCC supply current for one GTH Quad (4 lanes)	571	Note 2	mA
IMGTHAVCCRX	MGTHAVCCRX supply current for a GTH Quad (4 lanes)	254	Note 2	mA
IMGTHAVTT	MGTHAVTT supply current for one GTH Quad (4 lanes)	93	Note 2	mA
IMGTHAVCCPLL	MGTHAVCCPLL supply current for one GTH Quad (4 lanes)	219	Note 2	mA
MGTR _{REF}	Precision reference resistor for internal calibration termination	1000.0 ± 1% tolerance		Ω

Notes:

1. Typical values are specified at nominal voltage, 25°C, with a 10.3125 Gb/s line rate.
2. Values for currents other than the values specified in this table can be obtained by using the XPower Estimator (XPE) or XPower Analyzer (XPA) tools.

Table 29: GTH Transceiver Quiescent Supply Current⁽¹⁾⁽²⁾

Symbol	Description	Typ ⁽³⁾	Max	Units
IMGTHAVCCQ	Quiescent MGTHAVCC Supply Current for one GTH Quad (4 lanes)	65	Note 4	mA
IMGTHAVCCRQ	Quiescent MGTHAVCCRQ Supply Current for one GTH Quad (4 lanes)	17	Note 4	mA
IMGTHAVTTQ	Quiescent MGTHAVTT Supply Current for one GTH Quad (4 lanes)	1	Note 4	mA
IMGTHAVCCPLQ	Quiescent MGTHAVCCPLQ Supply Current for one GTH Quad (4 lanes)	1	Note 4	mA

Notes:

1. Device powered and unconfigured.
2. GTH transceiver quiescent supply current for an entire device can be calculated by multiplying the values in this table by the number of available GTH transceivers.
3. Typical values are specified at nominal voltage, 25°C.
4. Currents for conditions other than values specified in this table can be obtained by using the XPE or XPA tools.

GTH Transceiver Switching Characteristics

Consult [UG371: Virtex-6 FPGA GTH Transceivers User Guide](#) for further information.

Table 32: GTH Transceiver Maximum Data Rate and PLL Frequency Range

Symbol	Description	Conditions	Speed Grade			Units
			-3	-2	-1	
F_{GTHMAX}	Maximum GTH transceiver data rate	PLL Output Divider = 1	11.182	11.182	10.32	Gb/s
		PLL Output Divider = 4	2.795	2.795	2.58	Gb/s
F_{GTHMIN}	Minimum GTH transceiver data rate ⁽¹⁾	PLL Output Divider = 1	9.92	9.92	9.92	Gb/s
		PLL Output Divider = 4	2.48	2.48	2.48	Gb/s
$F_{GPLLMAX}$	Maximum GTH PLL frequency		5.591	5.591	5.16	GHz
$F_{GPLLMIN}$	Minimum GTH PLL frequency		4.96	4.96	4.96	GHz

Notes:

- Lower data rates can be achieved using FPGA logic based oversampling designs.

Table 33: GTH Transceiver Dynamic Reconfiguration Port (DRP) Switching Characteristics

Symbol	Description	Speed Grade			Units
		-3	-2	-1	
$F_{GTHDRPCLK}$	GTHDRPCLK maximum frequency	70	70	60	MHz

Table 34: GTH Transceiver Reference Clock Switching Characteristics

Symbol	Description	Conditions	All Speed Grades			Units
			Min	Typ	Max	
F_{GCLK}	Reference clock frequency range	-1 speed grade	150	–	645	MHz
		-2 and -3 speed grades	150	–	700	MHz
T_{RCLK}	Reference clock rise time	20% – 80%	–	200	–	ps
T_{FCLK}	Reference clock fall time	80% – 20%	–	200	–	ps
T_{DCREF}	Reference clock duty cycle	CLK	45	50	55	%
T_{LOCK}	Clock recovery frequency acquisition time	Initial PLL lock	–	–	2	ms
T_{PHASE}	Clock recovery phase acquisition time	Lock to data after PLL has locked to the reference clock	–	–	20	μs

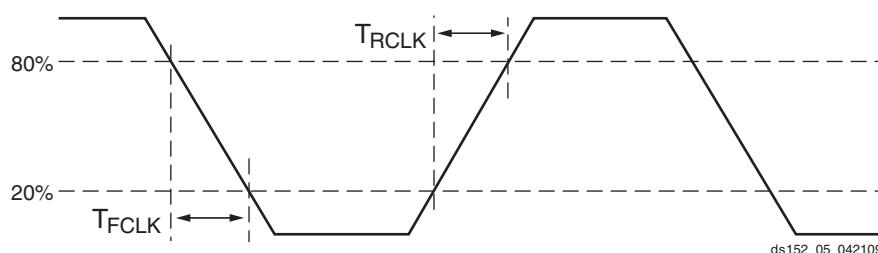


Figure 5: Reference Clock Timing Parameters

Table 35: GTH Transceiver User Clock Switching Characteristics (1)

Symbol	Description	Conditions	Speed Grade			Units
			-3	-2	-1	
F _{TXOUT}	TXUSERCLKOUT maximum frequency		350	350	323	MHz
F _{RXOUT}	RXUSERCLKOUT maximum frequency		350	350	323	MHz
F _{TXIN}	TXUSERCLKIN maximum frequency	16-bit data path	350	350	323	MHz
		20-bit data path	280	280	258	MHz
		32-bit data path	350	350	323	MHz
		40-bit data path	280	280	258	MHz
		64-bit data path	175	175	162	MHz
		80-bit data path	140	140	129	MHz
		64B/66B-bit data path	170	170	157	MHz
F _{RXIN}	RXUSERCLKIN maximum frequency	16-bit data path	350	350	323	MHz
		20-bit data path	280	280	258	MHz
		32-bit data path	350	350	323	MHz
		40-bit data path	280	280	258	MHz
		64-bit data path	175	175	162	MHz
		80-bit data path	140	140	129	MHz
		64B/66B-bit data path	170	170	157	MHz

Notes:

- Clocking must be implemented as described in [UG371: Virtex-6 FPGA GTH Transceivers User Guide](#).

Table 36: GTH Transceiver Transmitter Switching Characteristics

Symbol	Description	Condition	Min	Typ	Max	Units
T _{RTX}	TX Rise time	20%–80%	—	50 ⁽³⁾	—	ps
T _{FTX}	TX Fall time	80%–20%	—	50 ⁽³⁾	—	ps
T _{LLSKEW}	TX lane-to-lane skew	within one GTH Quad	—	—	300	ps
Transmitter Output Jitter⁽¹⁾⁽²⁾						
TJ _{11.18}	Total Jitter	11.181 Gb/s	—	—	0.280	UI
DJ _{11.18}	Deterministic Jitter		—	—	0.170	UI
TJ _{10.3125}	Total Jitter	10.3125 Gb/s	—	—	0.280	UI
DJ _{10.3125}	Deterministic Jitter		—	—	0.170	UI
TJ _{9.953}	Total Jitter	9.953 Gb/s	—	—	0.280	UI
DJ _{9.953}	Deterministic Jitter		—	—	0.170	UI
TJ _{2.667}	Total Jitter	2.667 Gb/s	—	—	0.110	UI
DJ _{2.667}	Deterministic Jitter		—	—	0.060	UI
TJ _{2.488}	Total Jitter	2.488 Gb/s	—	—	0.110	UI
DJ _{2.488}	Deterministic Jitter		—	—	0.060	UI

Notes:

- These values are NOT intended for protocol specific compliance determinations.
- All jitter values are based on a bit-error ratio of $1e^{-12}$.
- Rise and fall times are specified at the transmitter package balls.

Integrated Interface Block for PCI Express Designs Switching Characteristics

More information and documentation on solutions for PCI Express designs can be found at:
<http://www.xilinx.com/technology/protocols/pciexpress.htm>

Table 39: Maximum Performance for PCI Express Designs

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
F _{PIPECLK}	Pipe clock maximum frequency	250	250	250	250	MHz
F _{USERCLK}	User clock maximum frequency	500	500	250	250	MHz
F _{DRPCLK}	DRP clock maximum frequency	250	250	250	250	MHz

System Monitor Analog-to-Digital Converter Specification

Table 40: Analog-to-Digital Specifications

Parameter	Symbol	Comments/Conditions	Min	Typ	Max	Units
$AV_{DD} = 2.5V \pm 5\%$, $V_{REFP} = 1.25V$, $V_{REFN} = 0V$, ADCCLK = 5.2 MHz, $T_j = -55^{\circ}C$ to $125^{\circ}C$ M-Grade, Typical values at $T_j=+35^{\circ}C$						
DC Accuracy: All external input channels. Both unipolar and bipolar modes.						
Resolution			10	–	–	Bits
Integral Nonlinearity	INL		–	–	± 1	LSBs
Differential Nonlinearity	DNL	No missing codes (T_{MIN} to T_{MAX}) Guaranteed Monotonic	–	–	± 0.9	LSBs
Unipolar Offset Error ⁽¹⁾		Uncalibrated	–	± 2	± 30	LSBs
Bipolar Offset Error ⁽¹⁾		Uncalibrated measured in bipolar mode	–	± 2	± 30	LSBs
Gain Error		Uncalibrated - External Reference	–	± 0.2	± 2	%
		Uncalibrated - Internal Reference	–	± 2	–	%
Bipolar Gain Error ⁽¹⁾		Uncalibrated - External Reference	–	± 0.2	± 2	%
		Uncalibrated - Internal Reference	–	± 2	–	%
Total Unadjusted Error (Uncalibrated)	TUE	Deviation from ideal transfer function. External 1.25V reference	–	± 10	–	LSBs
		Deviation from ideal transfer function. Internal reference	–	± 20	–	LSBs
Total Unadjusted Error (Calibrated)	TUE	Deviation from ideal transfer function. External 1.25V reference	–	± 1	± 2	LSBs
Calibrated Gain Temperature Coefficient		Variation of FS code with temperature	–	± 0.01	–	LSB/ $^{\circ}C$
DC Common-Mode Reject	CMRR _{DC}	$V_N = V_{CM} = 0.5V \pm 0.5V$, $V_P - V_N = 100mV$	–	70	–	dB
Conversion Rate⁽²⁾						
Conversion Time - Continuous	t _{CONV}	Number of CLK cycles	26	–	32	
Conversion Time - Event	t _{CONV}	Number of CLK cycles	–	–	21	
T/H Acquisition Time	t _{Acq}	Number of CLK cycles	4	–	–	
DRP Clock Frequency	DCLK	DRP clock frequency	8	–	80	MHz
ADC Clock Frequency	ADCCLK	Derived from DCLK	1	–	5.2	MHz
CLK Duty cycle			40	–	60	%

Switching Characteristics

All values represented in this data sheet are based on these speed specifications: v1.17 for -3, -2, and -1; and v1.10 for -1L. Switching characteristics are specified on a per-speed-grade basis and can be designated as Advance, Preliminary, or Production. Each designation is defined as follows:

Advance

These specifications are based on simulations only and are typically available soon after device design specifications are frozen. Although speed grades with this designation are considered relatively stable and conservative, some under-reporting might still occur.

Preliminary

These specifications are based on complete ES (engineering sample) silicon characterization. Devices and speed grades with this designation are intended to give a better indication of the expected performance of production silicon. The probability of under-reporting delays is greatly reduced as compared to Advance data.

Production

These specifications are released once enough production silicon of a particular device family member has been characterized to provide full correlation between specifications and devices over numerous production lots. There is no under-reporting of delays, and customers receive formal notification of any subsequent changes. Typically, the slowest speed grades transition to Production before faster speed grades.

All specifications are always representative of worst-case supply voltage and junction temperature conditions.

Since individual family members are produced at different times, the migration from one category to another depends completely on the status of the fabrication process for each device.

[Table 42](#) correlates the current status of each Virtex-6 device on a per speed grade basis.

Table 42: Virtex-6 Device Speed Grade Designations

Device	Speed Grade Designations		
	Advance	Preliminary	Production
XC6VLX75T			-3, -2, -1, -1L
XC6VLX130T			-3, -2, -1, -1L
XC6VLX195T			-3, -2, -1, -1L
XC6VLX240T			-3, -2, -1, -1L
XC6VLX365T			-3, -2, -1, -1L
XC6VLX550T			-2, -1, -1L
XC6VLX760			-2, -1, -1L
XC6VSX315T			-3, -2, -1, -1L
XC6VSX475T			-2, -1, -1L
XC6VHX250T			-3, -2, -1
XC6VHX255T			-3, -2, -1
XC6VHX380T			-3, -2, -1
XC6VHX565T			-2, -1
XQ6VLX130T			-2, -1, -1L
XQ6VLX240T			-2, -1, -1L
XQ6VLX550T			-1, -1L
XQ6VSX315T			-2, -1, -1L
XQ6VSX475T			-1, -1L

Testing of Switching Characteristics

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values.

For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer and back-annotate to the simulation net list. Unless otherwise noted, values apply to all Virtex-6 devices.

Table 44: IOB Switching Characteristics for the Commercial (XC) Virtex-6 Devices (Cont'd)

I/O Standard	T _{IOP1}				T _{IOP2}				T _{IOTP}				Units	
	Speed Grade				Speed Grade				Speed Grade					
	-3	-2	-1	-1L	-3	-2	-1	-1L	-3	-2	-1	-1L		
LVCMOS25, Fast, 24 mA	0.51	0.57	0.66	0.70	1.66	1.79	1.99	1.96	1.66	1.79	1.99	1.96	ns	
LVCMOS18, Slow, 2 mA	0.55	0.61	0.71	0.73	4.21	4.47	4.87	4.30	4.21	4.47	4.87	4.30	ns	
LVCMOS18, Slow, 4 mA	0.55	0.61	0.71	0.73	2.79	2.96	3.21	2.94	2.79	2.96	3.21	2.94	ns	
LVCMOS18, Slow, 6 mA	0.55	0.61	0.71	0.73	2.30	2.43	2.64	2.47	2.30	2.43	2.64	2.47	ns	
LVCMOS18, Slow, 8 mA	0.55	0.61	0.71	0.73	2.01	2.11	2.27	2.24	2.01	2.11	2.27	2.24	ns	
LVCMOS18, Slow, 12 mA	0.55	0.61	0.71	0.73	1.88	1.99	2.15	2.10	1.88	1.99	2.15	2.10	ns	
LVCMOS18, Slow, 16 mA	0.55	0.61	0.71	0.73	1.84	1.95	2.11	2.04	1.84	1.95	2.11	2.04	ns	
LVCMOS18, Fast, 2 mA	0.55	0.61	0.71	0.73	4.00	4.23	4.57	4.08	4.00	4.23	4.57	4.08	ns	
LVCMOS18, Fast, 4 mA	0.55	0.61	0.71	0.73	2.62	2.76	2.97	2.74	2.62	2.76	2.97	2.74	ns	
LVCMOS18, Fast, 6 mA	0.55	0.61	0.71	0.73	2.15	2.28	2.46	2.32	2.15	2.28	2.46	2.32	ns	
LVCMOS18, Fast, 8 mA	0.55	0.61	0.71	0.73	1.90	1.99	2.13	2.14	1.90	1.99	2.13	2.14	ns	
LVCMOS18, Fast, 12 mA	0.55	0.61	0.71	0.73	1.69	1.80	1.97	1.88	1.69	1.80	1.97	1.88	ns	
LVCMOS18, Fast, 16 mA	0.55	0.61	0.71	0.73	1.63	1.74	1.91	1.88	1.63	1.74	1.91	1.88	ns	
LVCMOS15, Slow, 2 mA	0.64	0.73	0.85	0.85	3.43	3.77	4.29	3.91	3.43	3.77	4.29	3.91	ns	
LVCMOS15, Slow, 4 mA	0.64	0.73	0.85	0.85	2.58	2.79	3.10	2.93	2.58	2.79	3.10	2.93	ns	
LVCMOS15, Slow, 6 mA	0.64	0.73	0.85	0.85	2.08	2.32	2.68	2.50	2.08	2.32	2.68	2.50	ns	
LVCMOS15, Slow, 8 mA	0.64	0.73	0.85	0.85	1.81	1.98	2.23	2.24	1.81	1.98	2.23	2.24	ns	
LVCMOS15, Slow, 12 mA	0.64	0.73	0.85	0.85	1.76	1.91	2.13	2.07	1.76	1.91	2.13	2.07	ns	
LVCMOS15, Slow, 16 mA	0.64	0.73	0.85	0.85	1.69	1.83	2.04	1.98	1.69	1.83	2.04	1.98	ns	
LVCMOS15, Fast, 2 mA	0.64	0.73	0.85	0.85	3.44	3.77	4.28	3.91	3.44	3.77	4.28	3.91	ns	
LVCMOS15, Fast, 4 mA	0.64	0.73	0.85	0.85	2.37	2.53	2.78	2.66	2.37	2.53	2.78	2.66	ns	
LVCMOS15, Fast, 6 mA	0.64	0.73	0.85	0.85	1.80	2.05	2.42	2.16	1.80	2.05	2.42	2.16	ns	
LVCMOS15, Fast, 8 mA	0.64	0.73	0.85	0.85	1.76	1.90	2.11	2.04	1.76	1.90	2.11	2.04	ns	
LVCMOS15, Fast, 12 mA	0.64	0.73	0.85	0.85	1.64	1.77	1.97	1.90	1.64	1.77	1.97	1.90	ns	
LVCMOS15, Fast, 16 mA	0.64	0.73	0.85	0.85	1.62	1.76	1.96	1.92	1.62	1.76	1.96	1.92	ns	
LVCMOS12, Slow, 2 mA	0.72	0.81	0.93	0.95	3.14	3.39	3.75	3.54	3.14	3.39	3.75	3.54	ns	
LVCMOS12, Slow, 4 mA	0.72	0.81	0.93	0.95	2.43	2.63	2.93	2.79	2.43	2.63	2.93	2.79	ns	
LVCMOS12, Slow, 6 mA	0.72	0.81	0.93	0.95	1.92	2.11	2.41	2.26	1.92	2.11	2.41	2.26	ns	
LVCMOS12, Slow, 8 mA	0.72	0.81	0.93	0.95	1.87	2.02	2.25	2.17	1.87	2.02	2.25	2.17	ns	
LVCMOS12, Fast, 2 mA	0.72	0.81	0.93	0.95	2.71	2.98	3.39	3.11	2.71	2.98	3.39	3.11	ns	
LVCMOS12, Fast, 4 mA	0.72	0.81	0.93	0.95	1.93	2.16	2.51	2.31	1.93	2.16	2.51	2.31	ns	
LVCMOS12, Fast, 6 mA	0.72	0.81	0.93	0.95	1.75	1.89	2.11	2.05	1.75	1.89	2.11	2.05	ns	
LVCMOS12, Fast, 8 mA	0.72	0.81	0.93	0.95	1.69	1.82	2.02	1.98	1.69	1.82	2.02	1.98	ns	
LVDCI_25	0.51	0.57	0.66	0.70	2.05	2.14	2.26	2.26	2.05	2.14	2.26	2.26	ns	
LVDCI_18	0.55	0.61	0.71	0.73	2.07	2.23	2.47	2.38	2.07	2.23	2.47	2.38	ns	
LVDCI_15	0.64	0.73	0.85	0.85	1.85	2.01	2.24	2.18	1.85	2.01	2.24	2.18	ns	

Table 44: IOB Switching Characteristics for the Commercial (XC) Virtex-6 Devices (Cont'd)

I/O Standard	T _{IOPI}				T _{IOOP}				T _{IOTP}				Units	
	Speed Grade				Speed Grade				Speed Grade					
	-3	-2	-1	-1L	-3	-2	-1	-1L	-3	-2	-1	-1L		
DIFF_SSTL18_I	0.85	0.94	1.09	1.08	1.47	1.58	1.75	1.73	1.47	1.58	1.75	1.73	ns	
DIFF_SSTL18_I_DCI	0.85	0.94	1.09	1.08	1.40	1.51	1.67	1.65	1.40	1.51	1.67	1.65	ns	
DIFF_SSTL18_II	0.85	0.94	1.09	1.08	1.39	1.50	1.67	1.66	1.39	1.50	1.67	1.66	ns	
DIFF_SSTL18_II_DCI	0.85	0.94	1.09	1.08	1.36	1.47	1.63	1.62	1.36	1.47	1.63	1.62	ns	
DIFF_SSTL18_II_T_DCI	0.85	0.94	1.09	1.08	1.40	1.51	1.67	1.65	1.40	1.51	1.67	1.65	ns	
DIFF_SSTL15	0.81	0.91	1.06	1.06	1.42	1.54	1.71	1.69	1.42	1.54	1.71	1.69	ns	
DIFF_SSTL15_DCI	0.81	0.91	1.06	1.06	1.41	1.52	1.68	1.66	1.41	1.52	1.68	1.66	ns	
DIFF_SSTL15_T_DCI	0.81	0.91	1.06	1.06	1.41	1.52	1.68	1.66	1.41	1.52	1.68	1.66	ns	

Table 45: IOB Switching Characteristics for the Defense-grade (XQ) Virtex-6 Devices

I/O Standard	T _{IOPI}			T _{IOOP}			T _{IOTP}			Units	
	Speed Grade			Speed Grade			Speed Grade				
	-2	-1	-1L	-2	-1	-1L	-2	-1	-1L		
LVDS_25	0.94	1.09	1.08	1.54	2.16	1.62	1.54	2.16	1.62	ns	
LVDSEXT_25	0.94	1.09	1.08	1.65	2.20	1.73	1.65	2.20	1.73	ns	
HT_25	0.94	1.09	1.08	1.62	2.20	1.69	1.62	2.20	1.69	ns	
BLVDS_25	0.94	1.09	1.08	1.50	3.18	1.65	1.50	3.18	1.65	ns	
RSDS_25 (point to point)	0.94	1.09	1.08	1.54	2.22	1.62	1.54	2.22	1.62	ns	
HSTL_I	0.91	1.06	1.06	1.56	2.44	1.71	1.56	2.44	1.71	ns	
HSTL_II	0.91	1.06	1.06	1.56	2.21	1.72	1.56	2.21	1.72	ns	
HSTL_III	0.91	1.06	1.06	1.54	2.50	1.69	1.54	2.50	1.69	ns	
HSTL_I_18	0.91	1.06	1.06	1.58	2.43	1.72	1.58	2.43	1.72	ns	
HSTL_II_18	0.91	1.06	1.06	1.62	2.30	1.78	1.62	2.30	1.78	ns	
HSTL_III_18	0.91	1.06	1.06	1.54	2.49	1.69	1.54	2.49	1.69	ns	
SSTL2_I	0.91	1.06	1.06	1.60	2.50	1.74	1.60	2.50	1.74	ns	
SSTL2_II	0.91	1.06	1.06	1.54	2.49	1.71	1.54	2.49	1.71	ns	
SSTL15	0.91	1.06	1.06	1.54	2.07	1.69	1.54	2.07	1.69	ns	
LVCMOS25, Slow, 2 mA	0.57	0.66	0.70	5.46	6.01	5.63	5.46	6.01	5.63	ns	
LVCMOS25, Slow, 4 mA	0.57	0.66	0.70	3.49	3.79	3.65	3.49	3.79	3.65	ns	
LVCMOS25, Slow, 6 mA	0.57	0.66	0.70	2.81	3.08	2.95	2.81	3.08	2.95	ns	
LVCMOS25, Slow, 8 mA	0.57	0.66	0.70	2.41	2.72	2.59	2.41	2.72	2.59	ns	
LVCMOS25, Slow, 12 mA	0.57	0.66	0.70	1.95	2.23	2.10	1.95	2.23	2.10	ns	
LVCMOS25, Slow, 16 mA	0.57	0.66	0.70	2.05	2.29	2.21	2.05	2.29	2.21	ns	
LVCMOS25, Slow, 24 mA	0.57	0.66	0.70	1.82	2.24	1.98	1.82	2.24	1.98	ns	
LVCMOS25, Fast, 2 mA	0.57	0.66	0.70	5.49	6.04	5.62	5.49	6.04	5.62	ns	
LVCMOS25, Fast, 4 mA	0.57	0.66	0.70	3.50	3.82	3.65	3.50	3.82	3.65	ns	
LVCMOS25, Fast, 6 mA	0.57	0.66	0.70	2.73	2.99	2.88	2.73	2.99	2.88	ns	
LVCMOS25, Fast, 8 mA	0.57	0.66	0.70	2.33	2.65	2.53	2.33	2.65	2.53	ns	
LVCMOS25, Fast, 12 mA	0.57	0.66	0.70	1.88	2.08	2.03	1.88	2.08	2.03	ns	

Table 50: OLOGIC Switching Characteristics

Symbol	Description	Speed Grade					Units
		-3	-2	-1 (XC)	-1 (XQ)	-1L	
Setup/Hold							
T _{DCK/T_OCKD}	D1/D2 pins Setup/Hold with respect to CLK	0.45/ -0.08	0.50/ -0.08	0.54/ -0.08	0.54/ -0.08	0.69/ -0.11	ns
T _O OCECK/T _O CKOCE	OCE pin Setup/Hold with respect to CLK	0.17/ -0.03	0.20/ -0.03	0.22/ -0.03	0.27/ -0.05	0.27/ -0.04	ns
T _S SRCK/T _O CKSR	SR pin Setup/Hold with respect to CLK	0.59/ -0.24	0.62/ -0.24	0.54/ -0.08	0.54/ -0.08	0.79/ -0.35	ns
T _T TCK/T _O CKT	T1/T2 pins Setup/Hold with respect to CLK	0.44/ -0.07	0.51/ -0.07	0.56/ -0.07	0.60/ -0.10	0.68/ -0.13	ns
T _T TCECK/T _O CKTCE	TCE pin Setup/Hold with respect to CLK	0.15/ -0.04	0.19/ -0.04	0.21/ -0.04	0.27/ -0.05	0.29/ -0.05	ns
Combinatorial							
T _D OQ	D1 to OQ out or T1 to TQ out	0.78	0.87	1.01	1.01	1.15	ns
Sequential Delays							
T _O CKQ	CLK to OQ/TQ out	0.54	0.61	0.71	0.71	0.80	ns
T _R Q	SR pin to OQ/TQ out	0.80	0.90	1.05	1.05	1.19	ns
T _G SRQ	Global Set/Reset to Q outputs	7.60	7.60	10.51	10.51	10.51	ns
Set/Reset							
T _R PW	Minimum Pulse Width, SR inputs	0.78	0.95	1.20	1.20	1.30	ns, Min

Output Serializer/Deserializer Switching Characteristics

Table 52: OSERDES Switching Characteristics

Symbol	Description	Speed Grade					Units
		-3	-2	-1 (XC)	-1 (XQ)	-1L	
Setup/Hold							
T _{OSDCK_D} /T _{OSCKD_D}	D input Setup/Hold with respect to CLKDIV	0.23/ -0.10	0.28/ -0.10	0.31/ -0.10	0.35/ -0.10	0.36/ -0.15	ns
T _{OSDCK_T} /T _{OSCKD_T} ⁽¹⁾	T input Setup/Hold with respect to CLK	0.44/ -0.10	0.51/ -0.09	0.56/ -0.08	0.60/ -0.08	0.68/ -0.15	ns
T _{OSDCK_T2} /T _{OSCKD_T2} ⁽¹⁾	T input Setup/Hold with respect to CLKDIV	0.25/ -0.10	0.27/ -0.09	0.31/ -0.08	0.31/ -0.08	0.47/ -0.15	ns
T _{OSCCK_OCE} /T _{OSCKC_OCE}	OCE input Setup/Hold with respect to CLK	0.17/ -0.03	0.20/ -0.03	0.22/ -0.03	0.27/ -0.03	0.27/ -0.04	ns
T _{OSCCK_S}	SR (Reset) input Setup with respect to CLKDIV	0.07	0.07	0.07	0.07	0.08	ns
T _{OSCCK_TCE} /T _{OSCKC_TCE}	TCE input Setup/Hold with respect to CLK	0.15/ -0.04	0.19/ -0.04	0.21/ -0.04	0.27/ -0.04	0.29/ -0.05	ns
Sequential Delays							
T _{OSCKO_OQ}	Clock to out from CLK to OQ	0.63	0.71	0.82	0.82	0.93	ns
T _{OSCKO_TQ}	Clock to out from CLK to TQ	0.63	0.71	0.82	0.82	0.93	ns
Combinatorial							
T _{OSDO_TTQ}	T input to TQ Out	0.76	0.84	0.97	0.97	1.11	ns

Notes:

1. T_{OSDCK_T2} and T_{OSCKD_T2} are reported as T_{OSDCK_T}/T_{OSCKD_T} in TRACE report.

Block RAM and FIFO Switching Characteristics

Table 57: Block RAM and FIFO Switching Characteristics

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
Block RAM and FIFO Clock-to-Out Delays						
T _{RCKO_DO} and T _{RCKO_DO_REG} ⁽¹⁾	Clock CLK to DOUT output (without output register) ⁽²⁾⁽³⁾	1.60	1.79	2.08	2.36	ns, Max
	Clock CLK to DOUT output (with output register) ⁽⁴⁾⁽⁵⁾	0.60	0.66	0.75	0.83	ns, Max
T _{RCKO_DO_ECC} and T _{RCKO_DO_ECC_REG}	Clock CLK to DOUT output with ECC (without output register) ⁽²⁾⁽³⁾	2.62	2.89	3.30	3.73	ns, Max
	Clock CLK to DOUT output with ECC (with output register) ⁽⁴⁾⁽⁵⁾	0.71	0.77	0.86	0.94	ns, Max
T _{RCKO_CASC} and T _{RCKO_CASC_REG}	Clock CLK to DOUT output with Cascade (without output register) ⁽²⁾	2.49	2.77	3.18	3.61	ns, Max
	Clock CLK to DOUT output with Cascade (with output register) ⁽⁴⁾	1.29	1.41	1.58	1.79	ns, Max
T _{RCKO_FLAGS}	Clock CLK to FIFO flags outputs ⁽⁶⁾	0.74	0.81	0.91	0.98	ns, Max
T _{RCKO_POINTERS}	Clock CLK to FIFO pointers outputs ⁽⁷⁾	0.90	0.98	1.09	1.21	ns, Max
T _{RCKO_SDBIT_ECC} and T _{RCKO_SDBIT_ECC_REG}	Clock CLK to BITERR (with output register)	0.62	0.68	0.76	0.82	ns, Max
	Clock CLK to BITERR (without output register)	2.21	2.46	2.84	3.23	ns, Max
T _{RCKO_PARITY_ECC}	Clock CLK to ECCPARITY in ECC encode only mode	0.86	0.94	1.06	1.18	ns, Max
T _{RCKO_RDADDR_ECC} and T _{RCKO_RDADDR_ECC_REG}	Clock CLK to RDADDR output with ECC (without output register)	0.73	0.79	0.90	1.00	ns, Max
	Clock CLK to RDADDR output with ECC (with output register)	0.76	0.82	0.92	1.02	ns, Max
Setup and Hold Times Before/After Clock CLK						
T _{RCKC_ADDR} /T _{RCKC_ADDR}	ADDR inputs ⁽⁸⁾	0.47/ 0.27	0.53/ 0.29	0.62/ 0.32	0.66/ 0.34	ns, Min
T _{RDCK_DI} /T _{RCKD_DI}	DIN inputs ⁽⁹⁾	0.84/ 0.30	0.95/ 0.32	1.11/ 0.34	1.26/ 0.36	ns, Min
T _{RDCK_DI_ECC} /T _{RCKD_DI_ECC}	DIN inputs with block RAM ECC in standard mode ⁽⁹⁾	0.47/ 0.30	0.52/ 0.32	0.59/ 0.34	0.68/ 0.36	ns, Min
	DIN inputs with block RAM ECC encode only ⁽⁹⁾	0.68/ 0.30	0.75/ 0.32	0.85/ 0.34	0.97/ 0.36	ns, Min
	DIN inputs with FIFO ECC in standard mode ⁽⁹⁾	0.77/ 0.30	0.87/ 0.32	1.02/ 0.34	1.16/ 0.36	ns, Min
T _{RCKC_CLK} /T _{RCKC_CLK}	Inject single/double bit error in ECC mode	0.90/ 0.27	1.02/ 0.28	1.20/ 0.29	1.56/ 0.29	ns, Min
T _{RCKC_RDEN} /T _{RCKC_RDEN}	Block RAM Enable (EN) input	0.31/ 0.26	0.35/ 0.27	0.41/ 0.30	0.44/ 0.31	ns, Min
T _{RCKC_REGCE} /T _{RCKC_REGCE}	CE input of output register	0.18/ 0.25	0.19/ 0.27	0.22/ 0.31	0.24/ 0.33	ns, Min
T _{RCKC_RSTREG} /T _{RCKC_RSTREG}	Synchronous RSTREG input	0.22/ 0.23	0.24/ 0.24	0.28/ 0.26	0.31/ 0.27	ns, Min
T _{RCKC_RSTRAM} /T _{RCKC_RSTRAM}	Synchronous RSTRAM input	0.32/ 0.23	0.36/ 0.24	0.41/ 0.27	0.46/ 0.29	ns, Min

DSP48E1 Switching Characteristics

Table 58: DSP48E1 Switching Characteristics

Symbol	Description	Speed Grade					Units
		-3	-2	-1 (XC)	-1 (XQ)	-1L	
Setup and Hold Times of Data/Control Pins to the Input Register Clock							
$T_{DSPDCK_A, ACIN; B, BCIN}_AREG; BREG}$ / $T_{DSPCKD_A, ACIN; B, BCIN}_AREG; BREG}$	{A, ACIN, B, BCIN} input to {A, B} register CLK	0.25/ 0.27	0.29/ 0.30	0.35/ 0.34	0.36/ 0.34	0.46/ 0.39	ns
$T_{DSPDCK_C_CREG}/T_{DSPCKD_C_CREG}$	C input to C register CLK	0.16/ 0.20	0.19/ 0.22	0.22/ 0.24	0.25/ 0.24	0.33/ 0.30	ns
$T_{DSPDCK_D_DREG}/T_{DSPCKD_D_DREG}$	D input to D register CLK	0.07/ 0.31	0.10/ 0.34	0.15/ 0.39	0.16/ 0.39	0.24/ 0.45	ns
Setup and Hold Times of Data Pins to the Pipeline Register Clock							
$T_{DSPDCK_A, ACIN, B, BCIN}_MREG_MULT}$ / $T_{DSPCKD_A, ACIN, B, BCIN}_MREG_MULT$	{A, ACIN, B, BCIN} input to M register CLK	2.36/ 0.04	2.70/ 0.04	3.21/ 0.04	3.21/ 0.04	3.66/ 0.02	ns
$T_{DSPDCK_A, D}_ADREG$ / $T_{DSPCKD_A, D}_ADREG$	{A, D} input to AD register CLK	1.24/ 0.10	1.42/ 0.12	1.69/ 0.13	1.69/ 0.13	1.91/ 0.16	ns
Setup and Hold Times of Data/Control Pins to the Output Register Clock							
$T_{DSPDCK_A, ACIN, B, BCIN}_PREG_MULT}$ / $T_{DSPCKD_A, ACIN, B, BCIN}_PREG_MULT$	{A, ACIN, B, BCIN} input to P register CLK using multiplier	3.83/ -0.13	4.37/ -0.13	5.20/ -0.13	5.20/ -0.13	5.94/ -0.24	ns
$T_{DSPDCK_D_PREG_MULT}/T_{DSPCKD_D_PREG_MULT}$	D input to P register CLK	3.62/ -0.47	4.13/ -0.47	4.90/ -0.47	4.90/ -0.47	5.61/ -0.77	ns
$T_{DSPDCK_A, ACIN, B, BCIN}_PREG$ / $T_{DSPCKD_A, ACIN, B, BCIN}_PREG$	{A, ACIN, B, BCIN} input to P register CLK not using multiplier	1.59/ -0.13	1.81/ -0.13	2.15/ -0.13	2.15/ -0.13	2.44/ -0.24	ns
$T_{DSPDCK_C_PREG}/T_{DSPCKD_C_PREG}$	C input to P register CLK	1.42/ -0.10	1.61/ -0.10	1.91/ -0.10	1.91/ -0.10	2.16/ -0.19	ns
$T_{DSPDCK_PCIN, CARRYCASCIN, MULTSIGNIN}_PREG$ / $T_{DSPCKD_PCIN, CARRYCASCIN, MULTSIGNIN}_PREG$	{PCIN, CARRYCASCIN, MULTSIGNIN} input to P register CLK	1.23/ -0.02	1.41/ -0.02	1.67/ -0.02	1.67/ -0.02	1.91/ -0.07	ns
Setup and Hold Times of the CE Pins							
$T_{DSPDCK_CEA; CEB}_AREG; BREG}$ / $T_{DSPCKD_CEA; CEB}_AREG; BREG$	{CEA; CEB} input to {A; B} register CLK	0.14/ 0.19	0.17/ 0.22	0.22/ 0.25	0.22/ 0.25	0.30/ 0.28	ns
$T_{DSPDCK_CEC}_CREG/T_{DSPCKD_CEC}_CREG$	CEC input to C register CLK	0.15/ 0.18	0.18/ 0.20	0.24/ 0.23	0.24/ 0.23	0.31/ 0.26	ns
$T_{DSPDCK_CED}_DREG/T_{DSPCKD_CED}_DREG$	CED input to D register CLK	0.20/ 0.12	0.24/ 0.13	0.31/ 0.14	0.31/ 0.14	0.43/ 0.16	ns
$T_{DSPDCK_CEM}_MREG/T_{DSPCKD_CEM}_MREG$	CEM input to M register CLK	0.16/ 0.19	0.20/ 0.21	0.26/ 0.25	0.26/ 0.25	0.32/ 0.28	ns
$T_{DSPDCK_CEP}_PREG/T_{DSPCKD_CEP}_PREG$	CEP input to P register CLK	0.32/ 0.02	0.38/ 0.02	0.46/ 0.03	0.46/ 0.03	0.54/ 0.04	ns
Setup and Hold Times of the RST Pins							
$T_{DSPDCK_RSTA; RSTB}_AREG; BREG}$ / $T_{DSPCKD_RSTA; RSTB}_AREG; BREG$	{RSTA, RSTB} input to {A, B} register CLK	0.27/ 0.17	0.31/ 0.19	0.38/ 0.22	0.38/ 0.22	0.41/ 0.25	ns
$T_{DSPDCK_RSTC}_CREG/T_{DSPCKD_RSTC}_CREG$	RSTC input to C register CLK	0.18/ 0.08	0.20/ 0.08	0.23/ 0.09	0.23/ 0.09	0.27/ 0.11	ns
$T_{DSPDCK_RSTD}_DREG/T_{DSPCKD_RSTD}_DREG$	RSTD input to D register CLK	0.28/ 0.15	0.32/ 0.16	0.38/ 0.19	0.38/ 0.19	0.45/ 0.21	ns
$T_{DSPDCK_RSTM}_MREG/T_{DSPCKD_RSTM}_MREG$	RSTM input to M register CLK	0.20/ 0.24	0.23/ 0.26	0.26/ 0.30	0.26/ 0.30	0.29/ 0.34	ns

Table 58: DSP48E1 Switching Characteristics (Cont'd)

Symbol	Description	Speed Grade					Units
		-3	-2	-1 (XC)	-1 (XQ)	-1L	
T _{DSPDCK_RSTP_PREG} / T _{DSPCKD_RSTP_PREG}	RSTP input to P register CLK	0.26/ 0.04	0.30/ 0.04	0.35/ 0.05	0.35/ 0.05	0.43/ 0.06	ns
Combinatorial Delays from Input Pins to Output Pins							
T _{DSPDO_{A, B}_{P, CARRYOUT}_MULT}	{A, B} input to {P, CARRYOUT} output using multiplier	3.76	4.29	5.08	5.08	5.87	ns
T _{DSPDO_D_{P, CARRYOUT}_MULT}	D input to {P, CARRYOUT} output using multiplier	3.57	4.07	4.82	4.82	5.57	ns
T _{DSPDO_{A, B}_{P, CARRYOUT}}	{A, B} input to {P, CARRYOUT} output not using multiplier	1.55	1.76	2.07	2.07	2.41	ns
T _{DSPDO_{C, CARRYIN}_{P, CARRYOUT}}	{C, CARRYIN} input to {P, CARRYOUT} output	1.38	1.56	1.83	1.83	2.13	ns
Combinatorial Delays from Input Pins to Cascading Output Pins							
T _{DSPDO_{A; B}_{ACOUT; BCOUT}}	{A, B} input to {ACOUT, BCOUT} output	0.49	0.56	0.65	0.65	0.73	ns
T _{DSPDO_{A, B}_{PCOUT, CARRYCASOUT, MULTSIGNOUT}_MULT}	{A, B} input to {PCOUT, CARRYCASOUT, MULTSIGNOUT} output using multiplier	3.87	4.42	5.24	5.24	6.09	ns
T _{DSPDO_D_{PCOUT, CARRYCASOUT, MULTSIGNOUT}_MULT}	D input to {PCOUT, CARRYCASOUT, MULTSIGNOUT} output using multiplier	3.66	4.17	4.94	4.94	5.76	ns
T _{DSPDO_{A, B}_{PCOUT, CARRYCASOUT, MULTSIGNOUT}}	{A, B} input to {PCOUT, CARRYCASOUT, MULTSIGNOUT} output not using multiplier	1.64	1.86	2.19	2.19	2.60	ns
T _{DSPDO_{C, CARRYIN}_{PCOUT, CARRYCASOUT, MULTSIGNOUT}}	{C, CARRYIN} input to {PCOUT, CARRYCASOUT, MULTSIGNOUT} output	1.46	1.66	1.95	1.95	2.32	ns
Combinatorial Delays from Cascading Input Pins to All Output Pins							
T _{DSPDO_{ACIN, BCIN}_{P, CARRYOUT}_MULT}	{ACIN, BCIN} input to {P, CARRYOUT} output using multiplier	3.67	4.19	4.97	4.97	5.75	ns
T _{DSPDO_{ACIN, BCIN}_{P, CARRYOUT}}	{ACIN, BCIN} input to {P, CARRYOUT} output not using multiplier	1.43	1.63	1.92	1.92	2.25	ns
T _{DSPDO_{ACIN; BCIN}_{ACOUT; BCOUT}}	{ACIN, BCIN} input to {ACOUT, BCOUT} output	0.36	0.42	0.49	0.49	0.56	ns
T _{DSPDO_{ACIN, BCIN}_{PCOUT, CARRYCASOUT, MULTSIGNOUT}_MULT}	{ACIN, BCIN} input to {PCOUT, CARRYCASOUT, MULTSIGNOUT} output using multiplier	3.76	4.29	5.10	5.10	5.94	ns
T _{DSPDO_{ACIN, BCIN}_{PCOUT, CARRYCASOUT, MULTSIGNOUT}}	{ACIN, BCIN} input to {PCOUT, CARRYCASOUT, MULTSIGNOUT} output not using multiplier	1.52	1.73	2.05	2.05	2.44	ns
T _{DSPDO_{PCIN, CARRYCASIN, MULTSIGNIN}_{P, CARRYOUT}}	{PCIN, CARRYCASIN, MULTSIGNIN} input to {P, CARRYOUT} output	1.19	1.35	1.60	1.60	1.87	ns

Table 58: DSP48E1 Switching Characteristics (Cont'd)

Symbol	Description	Speed Grade					Units
		-3	-2	-1 (XC)	-1 (XQ)	-1L	
Maximum Frequency							
F _{MAX}	With all registers used	600	540	450	450	410	MHz
F _{MAX_PATDET}	With pattern detector	551	483	408	408	356	MHz
F _{MAX_MULT_NOMREG}	Two register multiply without MREG	356	311	262	262	224	MHz
F _{MAX_MULT_NOMREG_PATDET}	Two register multiply without MREG with pattern detect	327	286	241	241	211	MHz
F _{MAX_PREADD_MULT_NOADREG}	Without ADREG	398	347	292	292	254	MHz
F _{MAX_PREADD_MULT_NOADREG_PATDET}	Without ADREG with pattern detect	398	347	292	292	254	MHz
F _{MAX_NOPIPELINEREG}	Without pipeline registers (MREG, ADREG)	266	233	196	196	171	MHz
F _{MAX_NOPIPELINEREG_PATDET}	Without pipeline registers (MREG, ADREG) with pattern detect	250	219	184	184	160	MHz

Configuration Switching Characteristics

Table 59: Configuration Switching Characteristics

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
Power-up Timing Characteristics						
T _{PL} ⁽¹⁾	Program Latency	5	5	5	5	ms, Max
T _{POR} ⁽¹⁾	Power-on-Reset	15/55	15/55	15/55	15/60	ms, Min/Max
T _{CCLK}	CCLK (output) delay	400	400	400	400	ns, Min
T _{PROGRAM}	Program Pulse Width	250	250	250	250	ns, Min
Master/Slave Serial Mode Programming Switching						
T _{DCCK/T_{CCKD}}	DIN Setup/Hold, slave mode	4.0/0.0	4.0/0.0	4.0/0.0	4.5/0.0	ns, Min
T _{DSCCK/T_{SCCKD}}	DIN Setup/Hold, master mode	4.0/0.0	4.0/0.0	4.0/0.0	5.0/0.0	ns, Min
T _{CCO}	DOUT at 2.5V	6	6	6	7	ns, Max
	DOUT at 1.8V	6	6	6	7	ns, Max
F _{MCCK}	Maximum CCLK frequency, serial modes	105	105	105	70	MHz, Max
F _{MCCKTOL}	Frequency Tolerance, master mode with respect to nominal CCLK.	55	55	55	60	%
F _{MSCK}	Slave mode external CCLK	100	100	100	100	MHz
SelectMAP Mode Programming Switching						
T _{SMDCK/T_{SMCKD}}	SelectMAP Data Setup/Hold	4.0/0.0	4.0/0.0	4.0/0.0	5.5/0.0	ns, Min
T _{SMCSCCK/T_{SMCKCS}}	CSI_B Setup/Hold	4.0/0.0	4.0/0.0	4.0/0.0	5.5/0.0	ns, Min
T _{SMCKW/T_{SMWCK}}	RDWR_B Setup/Hold	10.0/0.0	10.0/0.0	10.0/0.0	16.0/0.0	ns, Min
T _{SMCKCSO}	CSO_B clock to out (330 Ω pull-up resistor required)	6	6	6	7	ns, Max
T _{SMCO}	CCLK to DATA out in readback at 2.5V	6	6	6	7	ns, Max
	CCLK to DATA out in readback at 1.8V	6	6	6	7	ns, Max

Table 70: Clock-Capable Clock Input Setup and Hold With MMCM

Symbol	Description	Device	Speed Grade				Units
			-3	-2	-1	-1L	
Input Setup and Hold Time Relative to Clock-capable Clock Input Signal for LVCMS25 Standard.⁽¹⁾							
T _{PSMMC} /T _{PHMMC}	No Delay Clock-capable Clock Input and IFF ⁽²⁾ with MMCM	XC6VLX75T	1.56/ -0.25	1.69/ -0.25	1.86/ -0.25	1.91/ -0.15	ns
		XC6VLX130T	1.64/ -0.25	1.78/ -0.25	1.95/ -0.25	2.00/ -0.14	ns
		XC6VLX195T	1.65/ -0.24	1.79/ -0.24	1.96/ -0.24	2.01/ -0.15	ns
		XC6VLX240T	1.65/ -0.24	1.79/ -0.24	1.96/ -0.24	2.01/ -0.15	ns
		XC6VLX365T	1.66/ -0.25	1.79/ -0.25	1.97/ -0.25	2.02/ -0.15	ns
		XC6VLX550T	N/A	1.97/ -0.24	2.16/ -0.24	2.19/ -0.14	ns
		XC6VLX760	N/A	2.39/ -0.20	2.63/ -0.20	2.21/ -0.10	ns
		XC6VSX315T	1.67/ -0.25	1.80/ -0.25	1.98/ -0.25	2.03/ -0.16	ns
		XC6VSX475T	N/A	1.98/ -0.29	2.17/ -0.29	2.21/ -0.20	ns
		XC6VHX250T	1.63/ -0.24	1.76/ -0.24	1.94/ -0.24	N/A	ns
		XC6VHX255T	1.63/ -0.19	1.76/ -0.19	1.99/ -0.19	N/A	ns
		XC6VHX380T	1.80/ -0.23	1.94/ -0.23	2.13/ -0.23	N/A	ns
		XC6VHX565T	N/A	1.94/ -0.08	2.13/ -0.08	N/A	ns
		XQ6VLX130T	N/A	1.78/ -0.25	1.95/ -0.25	2.00/ -0.14	ns
		XQ6VLX240T	N/A	1.79/ -0.24	1.96/ -0.24	2.01/ -0.15	ns
		XQ6VLX550T	N/A	N/A	2.16/ -0.24	2.19/ -0.14	ns
		XQ6VSX315T	N/A	1.80/ -0.25	1.98/ -0.25	2.03/ -0.16	ns
		XQ6VSX475T	N/A	N/A	2.17/ -0.29	2.21/ -0.20	ns

Notes:

1. Setup and Hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the Global Clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the Global Clock input signal using the fastest process, lowest temperature, and highest voltage.
2. IFF = Input Flip-Flop or Latch
3. Use IBIS to determine any duty-cycle distortion incurred using various standards.

Table 73: Sample Window

Symbol	Description	Device	Speed Grade				Units
			-3	-2	-1	-1L	
T _{SAMP}	Sampling Error at Receiver Pins ⁽¹⁾	All	510	560	610	670	ps
T _{SAMP_BUFI0}	Sampling Error at Receiver Pins using BUFI0 ⁽²⁾	All	300	350	400	440	ps

Notes:

1. This parameter indicates the total sampling error of Virtex-6 FPGA DDR input registers, measured across voltage, temperature, and process. The characterization methodology uses the MMCM to capture the DDR input registers' edges of operation. These measurements include:
 - CLK0 MMCM jitter
 - MMCM accuracy (phase offset)
 - MMCM phase shift resolution
 These measurements do not include package or clock tree skew.
2. This parameter indicates the total sampling error of Virtex-6 FPGA DDR input registers, measured across voltage, temperature, and process. The characterization methodology uses the BUFI0 clock network and IODELAY to capture the DDR input registers' edges of operation. These measurements do not include package or clock tree skew.

Table 74: Pin-to-Pin Setup/Hold and Clock-to-Out

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
Data Input Setup and Hold Times Relative to a Forwarded Clock Input Pin Using BUFI0						
T _{PSCS/T_{PHCS}}	Setup/Hold of I/O clock	-0.28/1.09	-0.28/1.16	-0.28/1.33	-0.18/1.79	ns
Pin-to-Pin Clock-to-Out Using BUFI0						
T _{CLOCKOFCS}	Clock-to-Out of I/O clock	4.22	4.59	5.22	5.63	ns

Revision History

The following table shows the revision history for this document:

Date	Version	Description of Revisions
06/24/09	1.0	Initial Xilinx release.
07/16/09	1.1	Revised the maximum V _{CCAUX} and V _{IN} numbers in Table 2, page 2 . Removed empty column from Table 3, page 3 . Revised specifications on Table 20, page 13 . Updated Table 38, page 22 and added notes 1 and 2. Revised T _{DLYCCO_RDY} , T _{IDELAYCTRL_RPW} , and T _{IDELAYPAT_JIT} in Table 53, page 41 . Updated Table 58, page 46 to more closely match the DSP48E1 speed specifications. Updated T _{TAPTCK/TCKTAP} in Table 59, page 49 . Updated XC6VLX130T parameters in Table 68 through Table 70, page 59 .
08/19/09	1.2	Added values for -1L voltages and speed grade in all pertinent tables. Added V _{FS} and notes to Table 1 and Table 2 . Removed DV _{PPIN} from the example in Figure 2 . Added networking applications to Table 41, page 25 . Changed and added to the block RAM F _{MAX} section in Table 57, page 44 including removing Note 12. Changed F _{PFDMAX} values and corrected units for T _{STATPHAOFFSET} and T _{OUTDUTY} in Table 64, page 52 . Updated Table 71, page 60 .
09/16/09	2.0	Added Virtex-6 HXT devices to entire document including GTH Transceiver Specifications . Updated speed specifications as described in Switching Characteristics , includes changes in Table 51 , Table 57 , Table 58 , and Table 66 through Table 70 . Comprehensive changes to Table 14 , Table 15 , and Table 16 . Added conditions to DV _{PPOUT} and revised description of T _{OSKEW} in Table 17 . Removed V _{ISE} specification and note from Table 18 . Added note 3 to Table 23 . Updated note 3 in Table 24 . Updated LVCMOS25 delays in Table 44 . Updated specification for T _{IOTPHZ} in Table 46 . Removed T _{BUFHSKREW} from Table 71, page 60 and added values for T _{BUFIOSKEW} . Added values in Table 74 .

Date	Version	Description of Revisions
02/08/11	2.12	Removed note 1 from Table 4 as the larger devices (XC6VLX550T, XC6VLX760, XC6VSX475T, and XC6VHX565T) are now offered in -2L. Updated Table 4 and Table 5 with data for the XC6VHX380T in the FF(G)1154 package. In Table 41 , updated -1L specification for DDR3. Added Note 1 to Table 42 . Moved the XC6VHX380T devices in the FF(G)1154 package to production release in Table 43 using ISE 12.4 software with current speed specifications. Updated description for F_{INDUTY} in Table 64 .
02/25/11	3.0	Designated the data sheet as Preliminary for all devices not already labeled production in Table 42 . Changed the XC6VHX380T devices in all packages to production status in Table 42 and Table 43 . Removed note 1 from Table 42 . Added maximum specifications to Table 25 . Updated $T_{HAVCC2HAVCCRX}$ in Table 27 . Updated the typical values and notes in Table 28 and Table 29 . Added values to Table 30 and Table 31 . In Table 34 , added values for T_{LOCK} and T_{PHASE} . Updated the values in Table 36 and added note 3. Updated Table 37 and added note 4.
03/21/11	3.1	Updated Table 2 including Note 7 . In Table 4 , added Note 3 and -2E, extended temperature range to the XC6VLX550T, XC6VLX760, XC6VSX475T, and XC6VHX380T devices, and added Note 5 for the XC6VHX565T. Updated Table 28 typical values. Updated the description for $F_{IDELAYCTRL_REF}$ in Table 53 . Updated F_{MCCK} in Table 59 .
04/01/11	3.2	Added T_j values for C, E, and I temperature ranges to Table 2 . Updated the I_{CCQ} values in Table 4 . Updated F_{GCLK} in Table 34 . Designated the data sheet as Production for all devices not already labeled production in Table 42 . Changed the XC6VHX255T and XC6VHX565T devices in all packages to production status in Table 42 and Table 43 . This included updates to the Virtex-6 Device Pin-to-Pin Output Parameter Guidelines and Virtex-6 Device Pin-to-Pin Input Parameter Guidelines for these devices. Production speed specifications for these devices are available using the speed specification v1.14 in the ISE 13.1 software update. Updated and added package skew values to Table 72 ; these values are correct with regards to previous production released speed specifications in software. Updated copyright page 1 and Notice of Disclaimer .
12/08/11	3.3	Production release of the Defense-grade XQ devices in Table 42 and Table 43 using ISE v13.3 v1.17 Patch for -2 and -1 speed specifications; and v1.10 for -1L speed specifications. Added the XQ6VLX130T, XQ6VLX240T, XQ6VLX550T, XQ6VSX315T, and XQ6VSX475T to the data sheet which included adding Table 45 . Updated T_j in Table 2 . In Table 40 , updated T_j for most specifications and added Note 4 . Added Note 4 to Table 41 . Added -1(XQ) speed specification columns only to Table 50 , Table 51 , Table 52 , and Table 58 . Updated V_{OD} in Table 8 , V_{OCM} in Table 9 , and V_{OCM} and V_{DIFF} in Table 10 . Updated the Power-On Power Supply Requirements section. In Table 27 , updated maximum specification for $T_{HAVCC2HAVCCRX}$ and added Note 3 . Updated T_j in Table 40 . In Table 41 , increased the DDR LVDS receiver (SPI-4.2) -1 speed grade performance value from 1.0 Gb/s to 1.1 Gb/s. In Table 60 , updated the F_{MAX} to add a separate row for the LX760 device values. The speed specifications in the software tools have always matched these values for the LX760, the data sheet is now correct. Updated the notes for $T_{OUTJITTER}$ in Table 64 .
01/12/12	3.4	Added the temperature range -2E to Note 5 in Table 4 .

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